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- [IJ84] **G. Crupi**, R. Kaul, C. Li, and R. K. Gupta, “The 2018 MTT-S Graduate Student Fellowship Awards,” accepted for publication in *IEEE Microwave Magazine*.
- [IJ83] G. Bosi, A. Raffo, F. Trevisan, V. Vadalà, **G. Crupi**, and G. Vannini, “Nonlinear-embedding design methodology oriented to LDMOS power amplifiers,” published online EarlyView in *IEEE Transactions on Power Electronics*.
- [IJ82] A. Caddemi, E. Cardillo, and **G. Crupi**, “Light activation of noise at microwave frequencies: A study on scaled GaAs HEMT’s,” *IET Circuits, Devices & Systems*, vol. 12, no. 3, pp. 242-248, May 2018.
- [IJ81] **G. Crupi**, A. Raffo, V. Vadalà, G. Avolio, D. M. M.-P. Schreurs, G. Vannini, and A. Caddemi, “Technology-independent analysis of the double current-gain peak in millimeter-wave FETs,” *IEEE Microwave and Wireless Components Letters*, vol. 28, no. 4, pp. 326-328, April 2018.
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